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| Notice of References Cited | Application/Control No. 10/601,783 | Applicant(s)/Patent Under Reexamination CHENG ET AL. | |
| | Examiner Marc E. Norman | Art Unit 3744 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-2003/0063437 A1 | 04-2003 | Kurihara, Kazuo | 361/688 |
| | B | US-2002/0020755 A1 | 02-2002 | Matsushita, Satoshi | 236/49.3 |
| | C | US-6,654,894 B2 | 11-2003 | Kaminski et al. | 713/300 |
| | D | US-6,643,128 B2 | 11-2003 | Chu et al. | 361/687 |
| | E | US-6,597,972 B2 | 07-2003 | Emberty et al. | 700/304 |
| | F | US-6,348,873 B1 | 02-2002 | Wang et al. | 340/635 |
| | G | US-6,172,611 B1 | 01-2001 | Hussain et al. | 340/584 |
| | H | US-6,134,667 | 10-2000 | Suzuki et al. | 713/300 |
| | I | US-5,543,632 | 08-1996 | Ashley, Donald J. | 257/48 |
| | J | US-5,526,289 | 06-1996 | Dinh et al. | 700/300 |
| | K | US-5,249,741 | 10-1993 | Bistline et al. | 236/49.3 |
| | L | US-4,722,669 | 02-1988 | Kundert, Warren R. | 417/32 |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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